



Initial Product/Process Change Notification

Document #: IPCN26343ZA

Issue Date: 09 Jul 2026

Title of Change:	Qualification for SO8FL and u8FL Package from Mold Compound G700LS to G700LAE	
Proposed Changed Material First Ship Date:	29 May 2027 or earlier if approved by customer	
Current Material Last Order Date:	N/A <i>Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.</i>	
Current Material Last Delivery Date:	N/A <i>The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory.</i>	
Product Category:	Active components – Discrete components	
Contact information:	Contact your local onsemi Sales Office	
PCN Samples Contact:	Contact your local onsemi Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.	
Additional Reliability Data:	Contact your local onsemi Sales Office	
Type of Notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customers. An IPCN is an advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 6 months prior to implementation of the change. In case of questions, contact <PCN.Support@onsemi.com>	
Change Category		
Category	Type of Change	
Process - Assembly	SEM-PA-11: Change of mold compound / encapsulation material	
Description and Purpose:		
onsemi wishes to inform customers of its plan to change the mold compound used in SO8FL and u8FL packages from G700LS to G700LAE at the onsemi Seremban, Malaysia manufacturing site. This change is being implemented to improve delamination performance after preconditioning.		
	From	To
Mold Compound	G700LS	G700LAE
There are no product material changes as a result of this change and no product marking change as a result of this change.		
There is no product marking change as a result of this change		
Reason / Motivation for Change:	Process/Materials Change	
Anticipated impact on fit, form, function, reliability, product safety or manufacturability:	The device will be qualified and validated based on the same Product Specification. No anticipated impacts.	

Sites Affected:

onsemi Sites

onsemi Seremban, Malaysia

External Foundry/Subcon Sites

None

Marking of Parts/ Traceability of Change:

No change

Qualification Plan:

QV DEVICE NAME : NVMFD6H840NLT1G

RMS: 101329

PACKAGE: SO8FL Dual (T8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFD040N10MCLT1G

RMS: 102365

PACKAGE: SO8FL Dual (PTNG)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		



Initial Product/Process Change Notification

Document #: IPCN26343ZA

Issue Date: 09 Jul 2026

QV DEVICE NAME : NVMFS3D6N10MCLT1G

RMS: 101197

PACKAGE: SO8FL HD (PTNG)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS5C604NLAFT1G

RMS: 101842

PACKAGE: SO8FL HD (T6)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS6H800NWFT1G

RMS: 104471

PACKAGE: SO8FL HD (T8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTF56H850NLWFTAG

RMS: 104474

PACKAGE: u8FL (T8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS9D6P04M8LTAG

RMS: 102571

PACKAGE: u8FL (MV8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : MBR8170TFSTXG

RMS: 102572

PACKAGE: u8FL (Schottky)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NTMFS002P03P8ZST1G

RMS: 104088

PACKAGE: SO8FL HD (PT8P)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=150°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRVB30H100MFST3G

RMS: 102309

PACKAGE: SO8FL HD (Schottky Planar)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRVTS30120MFST3G

RMS: 107925

PACKAGE: SO8FL HD (Trench Schottky)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS5832NLWFT1G

RMS: 105752

PACKAGE: SO8FL HD (T2)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMF55113PLWFT1G

RMS: 107924

PACKAGE: SO8FL HD (T1)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : MBR30170MFST1G

RMS: 110767

PACKAGE: SO8FL HD (Schottky Diode)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFWS015P03P8ZTAG

RMS: 106678

PACKAGE: u8FL (PT8P)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFWS002N04CLTAG

RMS: 106421

PACKAGE: u8FL (T6)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFWS027N10MCLTAG

RMS: 106696

PACKAGE: u8FL (PTNG)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTF5010N10MCLTAG

RMS: 106696

PACKAGE: u8FL (PTNG)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS5116PLWFTAG

RMS: 105753

PACKAGE: u8FL (T1)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRVHP820MFD1G

RMS: TBD

PACKAGE: SO8FL Dual (Rect Ultrafast)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		



Initial Product/Process Change Notification

Document #: IPCN26343ZA

Issue Date: 09 Jul 2026

QV DEVICE NAME : NVMFD5873NLWFT1G-UM

RMS: TBD

PACKAGE: SO8FL Dual (T2)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFD5C650NLT1G-01

RMS: TBD

PACKAGE: SO8FL Dual (T6)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		



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QV DEVICE NAME : NTMFS0D8N02P1ET1G

RMS: TBD

PACKAGE: SO8FL HD (PT11E)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVMFS9D6P04M8LT1G

RMS: TBD

PACKAGE: SO8FL HD (MV8)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NVTFS5826NLWFTWG

RMS: TBD

PACKAGE: u8FL (T2)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Gate Bias	JESD22-A108	Ta=175°C, 100% max rated Vgss	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

QV DEVICE NAME : NRTS6100TFSTAG

RMS: TBD

PACKAGE: u8FL (Trench Schottky)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=175°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C, mount form air to air	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		



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QV DEVICE NAME : NRVTS30120MFST3G

RMS: 107925

PACKAGE: SO8FL HD (Trench Schottky)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=90°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta= 175°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @ 260 °C	
Intermittent Operating Life	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc
Temperature Cycling	JESD22-A104	Ta= -65°C to +150°C, mount form air to air	1000 cyc
High Humidity High Temperature Reverse Bias	JESD22-A101	85°C, 85% RH, bias	1008 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
Resistance to Solder Heat	JESD22- B106	Ta = 265°C, 10 sec	
Solderability	JSTD002	Ta = 245°C, 5 sec	
Physical Dimension	JESD22-B120		

Estimated date for qualification completion: **1 August 2026**

Electrical Characteristics Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

Current Part Number	New Part Number	Qualification Vehicle
NVTF55C466NLWFETAG	#NONE	NVTFWS002N04CLTAG
NVTFWS015P03P8ZTAG	#NONE	NVTFWS015P03P8ZTAG
NVTF55C670NLWFTAG	#NONE	NVTFWS002N04CLTAG
NVTF55C658NLWFTAG	#NONE	NVTFWS002N04CLTAG
NVTF55C478NLWFTAG	#NONE	NVTFWS002N04CLTAG
NVTF55C471NLWFTAG	#NONE	NVTFWS002N04CLTAG
NVTF55C460NLWFTAG	#NONE	NVTFWS002N04CLTAG
NVTF54C13NWFETWG	#NONE	NVTFWS002N04CLTAG
NVTF54C13NWFETWG	#NONE	NVTFWS002N04CLTAG
NVTF54C305NWFETAG	#NONE	NVTFWS002N04CLTAG
NVTFWS003N04CTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS004N04CTAG	#NONE	NVTFWS002N04CLTAG



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NVTFWS005N04CTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS012P03P8ZTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS016N06CTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS020N06CTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS030N06CTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS070N10MCLTAG	#NONE	NVTFWS027N10MCLTAG
NVTF55C453NLWFETAG	#NONE	NVTFWS002N04CLTAG
NVTFWS027N10MCLTAG	#NONE	NVTFWS027N10MCLTAG
NVTF54C02NWFTAG	#NONE	NVTFWS002N04CLTAG
NVTF54C10NWFTAG	#NONE	NVTFWS002N04CLTAG
NVTF55C680NLWFHTAG	#NONE	NVTFWS002N04CLTAG
NVTF55C680NLWFETAG	#NONE	NVTFWS002N04CLTAG
NVTFWS008N04CTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS015N04CTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS024N06CTAG	#NONE	NVTFWS002N04CLTAG
NVTFWS040N10MCLTAG	#NONE	NVTFWS002N04CLTAG

PCN Product List Addendum for:

Customer Contact Name: Premier Farnell Dropbox

Customer Contact Email: productchangenotices@newark.com

Appendix A: Changed Products

PCN#: IPCN26343ZA
Issue Date: Jul 09, 2026

NWKC: PREMIER FARNELL

Product	Customer Part Number	Qualification Vehicle	New Part Number	Replacement Supplier
NVTFSSC478NLWFTAG	2775458	NVTFWS002N04CLTAG	#NONE	
NVTFSSC471NLWFTAG	2775457	NVTFWS002N04CLTAG	#NONE	
NVTFSSC02NWFTAG	3766230	NVTFWS002N04CLTAG	#NONE	
NVTFSSC680NLWFETAG	4843843	NVTFWS002N04CLTAG	#NONE	
NVTFSSC658NLWFTAG	2760526	NVTFWS002N04CLTAG	#NONE	